In the Claims

The following is a complete listing of the claims and replace all prior claims in the application:

- 1. (currently amended) A magnetic tunnel junction device, comprising:
 2 a first magnetic layer and a second magnetic layer, at least one of the first and the second
 3 magnetic layers configured to include diffusion components selected to adjust one or more
 4 properties of the tunnel junction device; and
 5 a barrier layer disposed between the first and the second magnetic layers comprising and
 6 incorporating diffusion components migrated from the at least one magnetic layer, wherein the
 7 migrated diffusion components adjust the one or more properties of the tunnel junction device.
- 2. (original) The device of claim 1, wherein the diffusion components are selected to reduce a series resistance of the barrier layer.
- 3. (original) The device of claim 1, wherein the diffusion components are selected to decrease a bandgap of the barrier layer.
- 4. (original) The device of claim 1, wherein the diffusion components are selected to passivate an interface of the barrier layer.
- 5. (original) The device of claim 1, wherein:
 the first magnetic layer is a pinned magnetic layer; and
 the second magnetic layer is a free magnetic layer.

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- 6. (original) The device of claim 1, wherein at least one of the first and the second magnetic layers is a multi-layer structure.
- 7. (original) The device of claim 1, wherein the at least one layer comprises an alloy of CoFe.

Appl. No. 10/629,884 SJO920030125US1/HITG.037PA Amdt. Dated December 7, 2004 Reply to Office Action of September 7, 2004

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diffusion components comprises AlZrO_x.

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(original) The device of claim 7, wherein the alloy of CoFe comprises CoFeHf. 8. 1 9. (original) The device of claim 8, wherein the CoFeHf comprises about 5 to about 1 2 10 atomic percent Hf. 10. (original) The device of claim 7, wherein the alloy including CoFe comprises 1 2 CoFeZr. 11. 1 (original) The device of claim 10, wherein the CoFeZr comprises about 5 to about 2 10 atomic percent Zr. 12. (original) The device of claim 1, wherein the diffusion components comprise Hf. 1 13. (original) The device of claim 1, wherein the diffusion components comprise Zr. 1 14. (currently amended) The device of claim 1, wherein the barrier layer has a 1 thickness of about 3 to about 6 Å[[Å 11. 2 15. (original) The device of claim 1, wherein the barrier layer including the migrated 1 2 diffusion components comprises AlHfO_x.

(original) The device of claim 1, wherein the barrier layer including the migrated

17. (currently amended) A magnetic tunnel junction sensor, comprising: 1 2 a magnetic tunnel junction device comprising: a first magnetic layer and a second magnetic layer, at least one of the first and the 3 second magnetic layers configured to include diffusion components selected to adjust one 4 or more properties of the tunnel junction device; and 5 a barrier layer between the first and the second magnetic layers, the barrier layer 6 comprising migrated diffusion components from the at least one magnetic layer, wherein 7 the migrated diffusion components adjust the one or more properties; 8 a current source coupled to the first magnetic layer and the second magnetic layer; and 9 10 a magnetoresistance detector, coupled to the first and the second magnetic layers, for 11 detecting an electrical resistance through the magnetic tunnel junction device based on magnetic 12 orientations of the first and the second magnetic layers. 18. 1 (original) The device of claim 17, wherein the diffusion components are selected 2 to reduce a series resistance of the barrier layer. 19. 1 (original) The device of claim 17, wherein the diffusion components are selected to decrease a bandgap of the barrier layer. 2 20. 1 (original) The device of claim 17, wherein the second magnetic layer is a free magnetic layer. 2 1 21. (original) The device of claim 17, wherein the first magnetic layer is a pinned multi-layer magnetic structure. 2 22. (original) The device of claim 17, wherein the first magnetic layer comprises an 1 2 alloy of CoFe. (original) The device of claim 17, wherein the alloy of CoFe comprises CoFeHf. 23. 1 (original) The device of claim 17, wherein the alloy of CoFe comprises CoFeZr. 1 24.

1	25.	(original) The device of claim 17, wherein the diffusion components comprise
2	Hf.	
1	26.	(original) The device of claim 17, wherein the diffusion components comprise Zr.
1	27.	(currently amended) The device of claim 17, wherein the barrier layer has a
2	thickness of at	oout 3 to about 6 <u>Å</u> [[Å 11.
1	28.	(original) The device of claim 17, wherein the barrier layer including the
2	migrated diffu	sion components comprises AlHfO _x .
1	29.	(original) The device of claim 17, wherein the barrier layer including the
2	migrated diffu	sion components comprises AlZrO _x .
1	30.	(currently amended) A magnetic storage system, comprising:
2	a mova	able magnetic recording medium;
3	a magn	netic tunnel junction sensor for detecting magnetic signals on the moveable
4	recording med	ium, comprising:
5		a first magnetic layer and a second magnetic layer, at least one of the first and the
6	second	magnetic layers configured to include diffusion components selected to adjust one
7	or more	e properties of the tunnel junction sensor;
8		a barrier layer between the first and the second magnetic layers, the barrier layer
9	includi	ng migrated diffusion components from the at least one magnetic layer, wherein
10	the migrated diffusion components adjust the one or more properties; and	
11		a magnetoresistance detector, coupled to the first and the second magnetic layers,
12	for dete	ecting an electrical resistance through the magnetic tunnel junction sensor based on
13	magnet	tic orientations of the first and the second magnetic layers; and
14	an actu	ator, coupled to the magnetic tunnel junction sensor, for moving the sensor
15	relative to the	medium.

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2	second magnetic layers comprises an alloy of CoFe.	
1	32. (original) The device of claim 31, wherein the alloy of CoFe comprises CoFeH:	f.
1	33. (original) The device of claim 31, wherein the alloy of CoFe comprises CoFeZr	r.
1 2	34. (original) The device of claim 30, wherein the diffusion components comprise If.	
1	35. (original) The device of claim 30, wherein the diffusion components comprise 2	Zı
1	36. (original) The device of claim 30, wherein the barrier layer including the	
2	nigrated diffusion components comprises AlHfO _x .	
1	37. (original) The device of claim 30, wherein the barrier layer including the	
2	nigrated diffusion components comprises AlZrO _x .	
1	38. (currently amended) A memory device, comprising:	
2	an array of memory elements configured to store information for later access, each	
3	nemory element comprising:	
4	a first magnetic layer and a second magnetic layer, at least one of the first and th	ıe
5	second magnetic layers configured to include diffusion components selected to adjust or	ne
5	or more properties of the memory element; and	
7	a barrier layer between the first and the second magnetic layers, the barrier layer	
3	omprising migrated diffusion components from the at least one magnetic layer, wherein the	

(original) The device of claim 30, wherein the at least one of the first and the

migrated diffusion components adjust the one or more properties.

Appl. No. 10/629,884 SJO920030125US1/HITG.037PA Amdt. Dated December 7, 2004 Reply to Office Action of September 7, 2004

1	39. (currently amended) A tunnel junction device, comprising:		
2	means for providing a first magnetic layer incorporating diffusion components		
3	selected to adjust one or more properties of the tunnel junction device;		
4	means for providing a second magnetic layer;		
5	means for providing a tunnel barrier layer between the first and the second		
6	magnetic layers, the tunnel barrier layer including migrated diffusion components from the first		
7	magnetic layer, wherein the migrated diffusion components adjust the one or more properties of		
8	the tunnel junction device.		
1	40. (currently amended) A magnetic tunnel junction sensor, comprising:		
2	means for providing a first magnetic layer configured to include diffusion		
3	components selected to adjust one or more properties of the tunnel junction sensor; and		
4	means for providing a second magnetic layer;		
5	means for providing a barrier layer between the first and the second magnetic		
6	layers, the barrier layer comprising migrated diffusion components from the first		
7	magnetic layer, wherein the migrated diffusion components alter the one or more		
8	properties; and		
9	means for measuring an electrical resistance through the first and the second magnetic		
10	layers and the barrier layer based on magnetic orientations of the first and the second magnetic		
11	layers.		

Appl. No. 10/629,884 SJO920030125US1/HITG.037PA Amdt. Dated December 7, 2004 Reply to Office Action of September 7, 2004

1	41. (currently amended) A magnetic storage system, comprising:
2	means for storing magnetic data;
3	means for sensing the magnetically stored data, comprising:
4	means for providing a first magnetic layer configured to include diffusion
5	components selected to alter one or more properties of the sensing means;
6	means for providing a second magnetic layer; and
7	means for providing a barrier layer between the first and the second magnetic
8	layers, the barrier layer including diffusion components migrated from the first magnetic
9	layer and altering the one or more properties; and
10	means for detecting an electrical resistance through the means for sensing based
11	on magnetic orientations of the first and the second magnetic layers; and
12	means for moving the means for sensing relative to the means for magnetic data storage.